## Notice of References Cited

Application/Control No. 10/771,669		Applicant(s)/Patent Under Reexamination LEE ET AL.		
Examiner	Art Unit			
KENT WANG	2622	Page 1 of 1		

## U.S. PATENT DOCUMENTS

				Old Control of Control	
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0005707	01-2002	Kerai et al.	320/106
*	В	US-6,650,089	11-2003	Freeman et al.	320/132
*	С	US-6,946,817	09-2005	Fischer et al.	320/132
*	D	US-6,151,652	11-2000	Kondo et al.	713/300
*	Е	US-2003/0148663	08-2003	Hsin, Liao Sheng	439/638
*	F	US-2004/0203275	10-2004	Jeansonne et al.	439/378
*	G	US-6,424,123	07-2002	Odaohhara et al.	320/134
*	Н	US-6,798,173	09-2004	Hsu, Ying-Hao	320/134
*	T	US-5,870,615	02-1999	Bar-On et al.	713/310
*	J	US-5,606,704	02-1997	Pierce et al.	713/322
*	к	US-5,561,772	10-1996	Dornier et al.	710/300
*	L	US-6,128,040	10-2000	Shinbori et al.	348/372
	м	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## NON-PATENT DOCUMENTS

NON-FAIENT DOCUMENTS		
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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